



**IEEE802.3 4P Task Force  
Channel Pair To Pair Resistance  
Imbalance**

**Investigation of a low resistance  
connector / Rev.2**

# IEC 60603-7 (Ed.3)- Summary of specifications

- › **Input to output d.c. resistance (6.4.5):**  
Mated connectors  
***200mΩ maximum***
- › **Initial contact resistance (6.4.4):**  
Contact interface only  
***20mΩ maximum***
- › **Input to output d.c.resistance unbalance (6.4.6):**  
Mated connectors, max. difference between max. and min. (from 6.4.5)  
***50mΩ maximum***
- › **Environmental or mechanical “aging”:**  
***20mΩ maximum Contact resistance change from initial***

# IEC 60603-7

- For the worst case model of the Ad-hoc, (minimum resistance, maximum unbalance) the maximum values according 60603-7 ( $200m\Omega$  /  $50m\Omega$ ) are probably too high/not relevant.

*But also a low resistance connector is affected by aging (environmental stress, mechanical operation,..) which would increase the initial resistance unbalance over lifetime.*

- To increase the database for the Ad-hoc model, this document lists the resistance test data of a specific low resistance RJ-45.

# Resistance measurements on samples

- › **Product:**  
**Short Top Entry RJ-45 connector with low input to output resistance.**



- › **Testing and test references according IEC 60603-7:**  
**Jack mounted on PCB, mated connections measured with standard RJ-45 plug (short cable terminations)**



# Results (Initial):

## › Input to output d.c. resistance 6.4.5 (initial)

Mated connectors, cable termination (plug) to mounting PCB (jack).

**22** samples @8 contacts:

**23.34** mΩ Max

**20.19** mΩ Mean

**17.84** mΩ Min)

## › Resistance unbalance 6.4.6 (initial):

Mated connectors, difference between min. and max.

**5.2** mΩ maximum unbalance

## › Initial Contact Resistance 6.4.4

(without bulk resistance of connection)

**11.1 / 7.9 / 6.9** (mΩ Max/Mean/Min)

# Results (Aging)

## Changes from initial resistance:

- › **AP**-Thermal Stress / Cyclic damp heat (8 samples):  
**3.1 / 1.3 / -0.9** (mΩ Max/Mean/Min)
- › **BP**-Flowing Mix Gas/Corrosion and mechanical operation (8 samples):
  - a) 1250cycles (1st half) + FMG corrosion (BP4):  
**8.0 / 0.4 / -1.4** ( mΩ Max/Mean/Min)
  - b) further 1250 cycles mech. operation (BP6)  
**4.0 / 1.0 / -0.9** (mΩ Max/Mean/Min)
- › **CP**-Vibration (10 samples)  
**0.3 / -0.4 / -1.3** (mΩ Max/Mean/Min)
- › **DP**-Electrical load and temperature (6 samples)  
**3.1 / 0.0 / -3.4** (mΩ Max/Mean/Min)

# Summary of testing

- The influence of aging (corrosion, mechanical operation, load+temp.) to the initial resistance of a connection is higher than the initial resistance unbalance between contacts (\*).
- Aging can increase or reduce contact resistance

(\*) It has to be considered that the investigated jack has NiPd plating which offers a high contact reliability.

A similar jack with a low quality plating could show a higher change of the contact resistance after aging.

This result is for a specific jack. A more complex jack (fully Cat6<sub>A</sub>) could have a higher initial resistance unbalance but probably also a higher resistance in general.

# Summary of testing

## › d.c. Resistance of connection (plug and jack) 22 samples:

- Minimum 17.84 mΩ initial only
- Minimum 17.53 mΩ with aging
- Maximum 23.34 mΩ initial only
- Maximum 29.47 mΩ with aging

## › Resistance unbalance (from above)

- Maximum 5.2 mΩ initial only
- Maximum 11.94 mΩ with aging